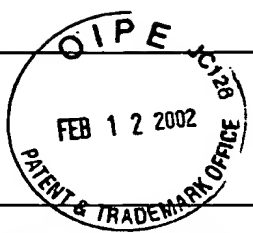


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U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

<b>INFORMATION DISCLOSURE STATEMENT</b>		Docket Number: <b>TECHNOLOGY CENTER 2600 2509/71</b>	
Application Number <b>09/819,449</b>	Filing Date <b>March 28, 2001</b>	Examiner <b>Not Yet Assigned</b>	Art Unit <b>2852</b>
Invention Title <b>SYSTEM AND METHOD OF THREE-DIMENSIONAL IMAGE CAPTURE AND MODELING</b>		Inventors <b>PETROV, et al.</b>	

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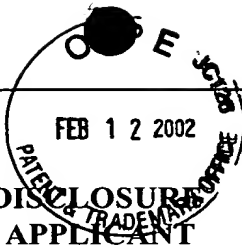
1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant hereby bring the references listed on the attached modified PTO Form No. 1449 to the attention of the Examiner. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
2. A copy of each patent, publication or other information listed on the modified PTO form 1449 is enclosed, except as otherwise indicated.
3. The Commissioner is authorized to charge any fees or credit any overpayment in connection with this paper to Deposit Account No. 11-0600.

Dated: 2/1/02

By:   
Paul T. Qualey (Reg. No. 43,027)  
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I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Assistant Commissioner of Patents, Washington, D.C. 20231, on

Date 2/1/02 Atty's Reg. # \_\_\_\_\_  
Atty's Signature   
KENYON & KENYON



**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT  
PTO-1449**

**ATTY. DOCKET NO.**  
**2509/71**

**SERIAL NO.**  
**09/819,449**

**APPLICANT**  
**PETROV, et al.**

**FILING DATE**  
**March 28, 2001**

**GROUP**  
**2852**

**U. S. PATENT DOCUMENTS**

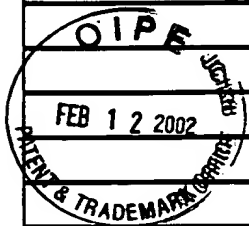
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	5,164,793	November 17, 1992	WOLFERSBERGER, et al.
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	4,871,256	October 3, 1989	GRINDON
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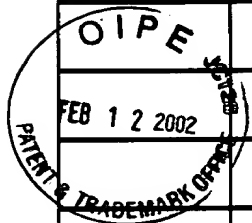
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EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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